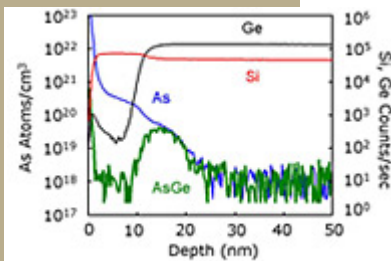


Secondary Ion Mass Spectrometry (SIMS)



Secondary Ion Mass Spectrometry (SIMS)



Instruments

- Physical Electronics ADEPT-1010 quad SIMS

Applications

- Ultra shallow dopant profiling
- Ultra thin film characterization

Technical Specifications

- Ultra high depth resolution (<1 nm/decade)

For information or to arrange a demonstration please contact the New Pioneers in Surface Analysis Technology:

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